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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	147456
Number of I/O	97
Number of Gates	1000000
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TJ)
Package / Case	144-LBGA
Supplier Device Package	144-FPBGA (13x13)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a3p1000-fg144m

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- JTAG supply, PLL power supplies, and charge pump VPUMP supply have no influence on I/O behavior.

PLL Behavior at Brownout Condition

Microsemi recommends using monotonic power supplies or voltage regulators to ensure proper power-up behavior. Power ramp-up should be monotonic, at least until VCC and VCCPLX exceed brownout activation levels. The VCC activation level is specified as 1.1 V worst-case (see [Figure 2-1](#) and [Figure 2-2](#) on page 2-5 for more details).

When PLL power supply voltage and/or VCC levels drop below the VCC brownout levels ($0.75\text{ V} \pm 0.25\text{ V}$), the PLL output lock signal goes low and/or the output clock is lost. Refer to the "Power-Up-/Down Behavior of Low-Power Flash Devices" chapter of the [Military ProASIC3/EL FPGA Fabric User's Guide](#) for information on clock and lock recovery.

Internal Power-Up Activation Sequence

1. Core
2. Input buffers

Output buffers, after 200 ns delay from input buffer activation.

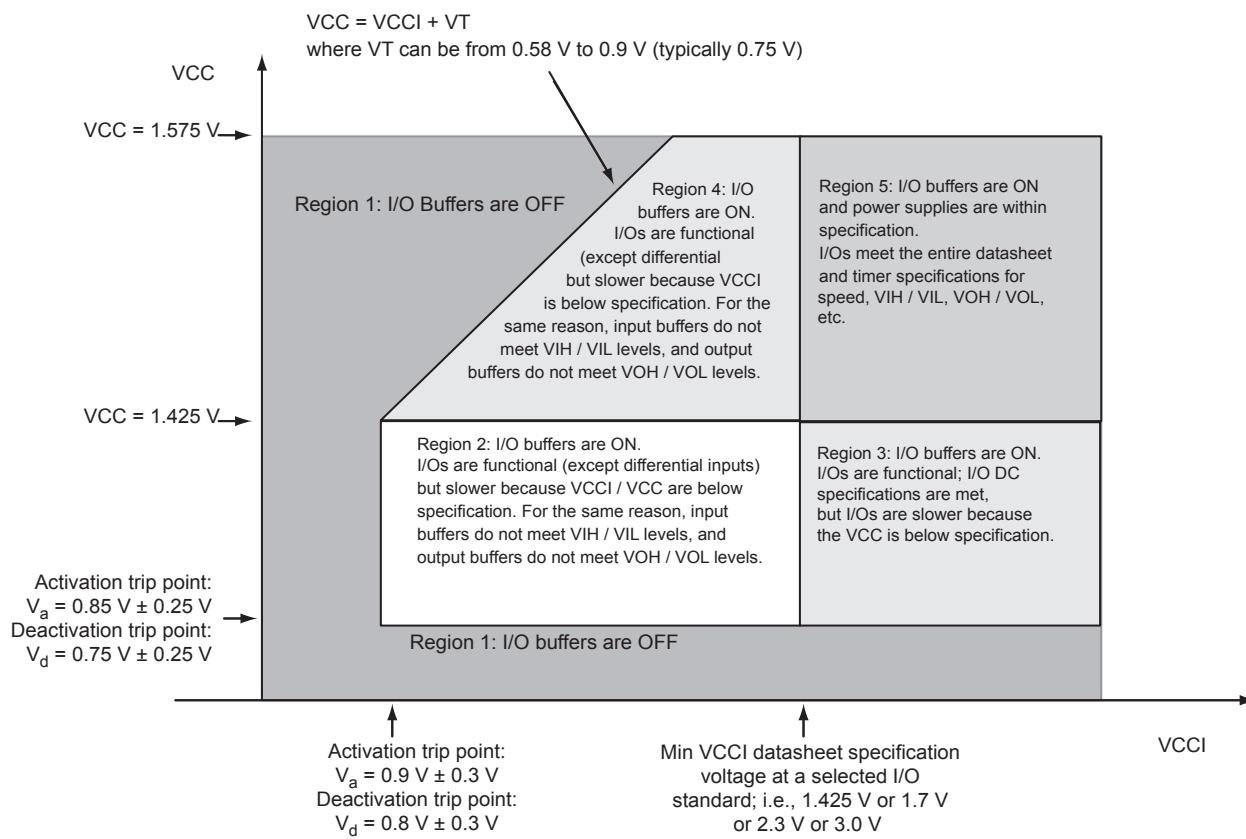


Figure 2-1 • Devices Operating at 1.5 V Core – I/O State as a Function of VCCI and VCC Voltage Levels

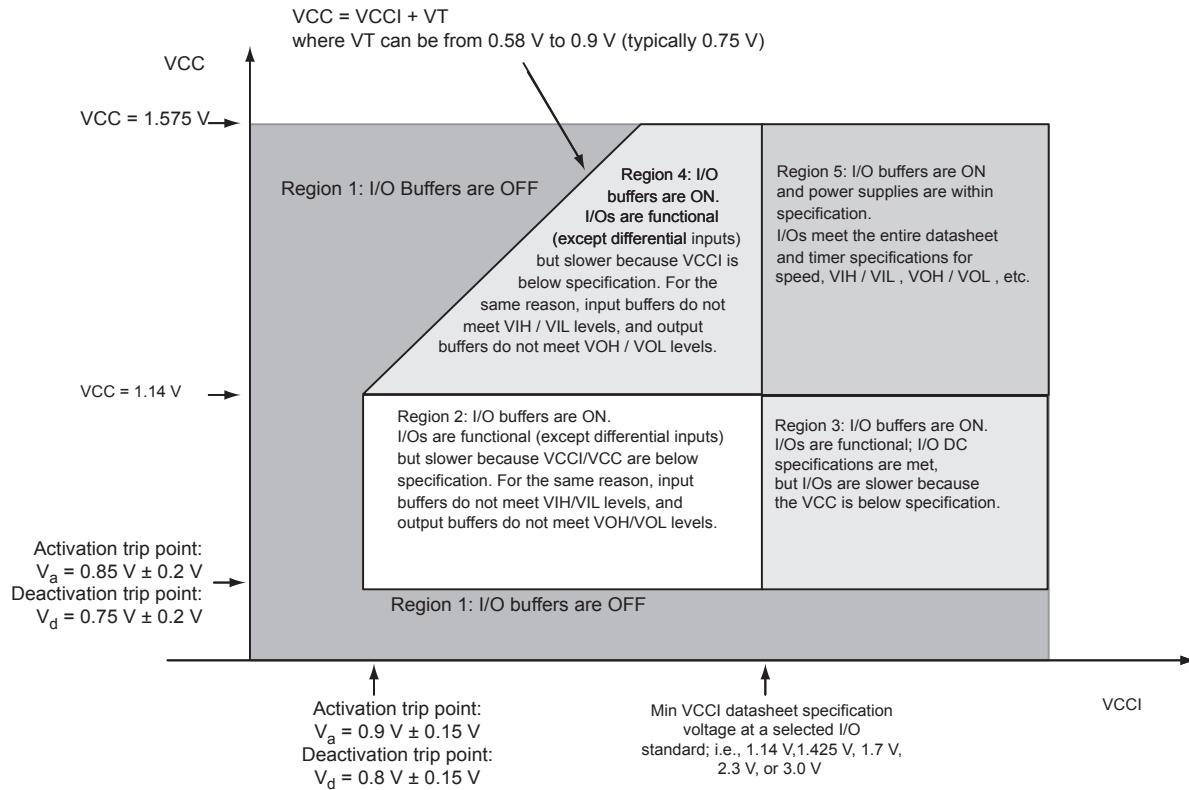


Figure 2-2 • Device Operating at 1.2 V Core Voltage – I/O State as a Function of VCCI and VCC Voltage Levels; Only A3PE600L and A3PE3000L Devices Operate at 1.2 V Core Voltage

Thermal Characteristics

Introduction

The temperature variable in the Designer software refers to the junction temperature, not the ambient temperature. This is an important distinction because dynamic and static power consumption cause the chip junction temperature to be higher than the ambient temperature.

EQ 1 can be used to calculate junction temperature.

$$T_J = \text{Junction Temperature} = \Delta T + T_A \quad \text{EQ 1}$$

where:

T_A = Ambient Temperature

ΔT = Temperature gradient between junction (silicon) and ambient $\Delta T = \theta_{ja} * P$

θ_{ja} = Junction-to-ambient of the package. θ_{ja} numbers are located in Table 2-5.

P = Power dissipation

Package Thermal Characteristics

The device junction-to-case thermal resistivity is θ_{jc} and the junction-to-ambient air thermal resistivity is θ_{ja} . The thermal characteristics for θ_{ja} are shown for two air flow rates. The recommended maximum junction temperature is 125°C. EQ 2 shows a sample calculation of the recommended maximum power dissipation allowed for a 484-pin FBGA package at military temperature and in still air.

$$\text{Maximum Power Allowed} = \frac{\text{Max. junction temp. } (\text{°C}) - \text{Max. ambient temp. } (\text{°C})}{\theta_{ja} (\text{°C/W})} = \frac{125^\circ\text{C} - 70^\circ\text{C}}{20.6^\circ\text{C/W}} = 2.670$$

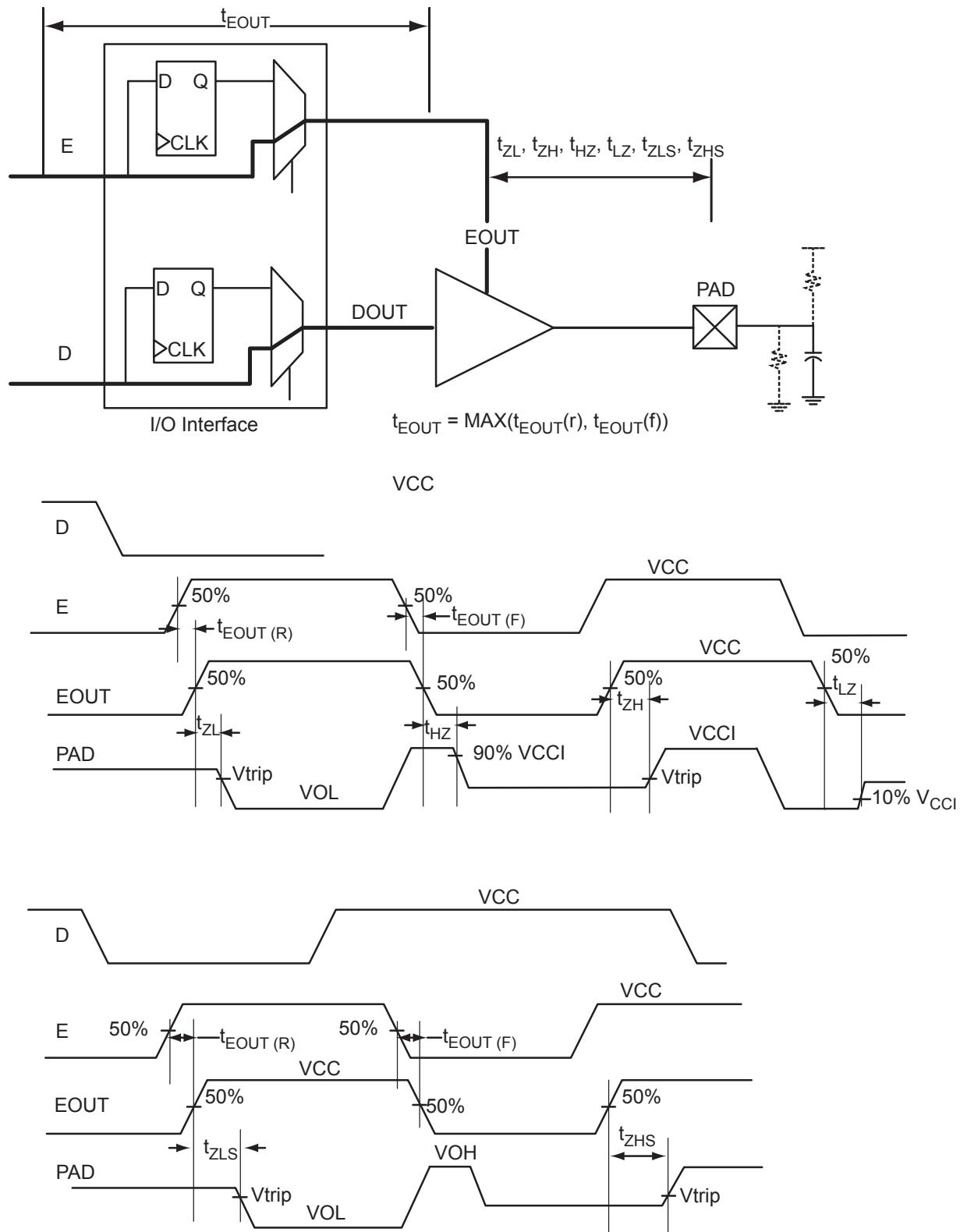


Figure 2-6 • Tristate Output Buffer Timing Model and Delays (example)

Timing Characteristics

1.2 V DC Core Voltage

Table 2-108 • 1.2 V LVC MOS Low Slew

Military-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 1.4 V

Applicable to Pro I/O Banks for A3PE600L and A3PE3000L Only

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{PYS}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	0.80	12.61	0.05	2.65	3.75	0.52	12.10	9.50	5.11	4.66	14.31	11.71	ns
	-1	0.68	10.72	0.05	2.25	3.19	0.44	10.30	8.08	4.35	3.97	12.17	9.96	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

Table 2-109 • 1.2 V LVC MOS High Slew

Military-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 1.4 V

Applicable to Pro I/O Banks for A3PE600L and A3PE3000L Only

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{PYS}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	0.80	5.16	0.05	2.65	3.75	0.52	4.98	4.39	5.10	4.81	7.19	6.60	ns
	-1	0.68	4.39	0.05	2.25	3.19	0.44	4.24	3.74	4.34	4.09	6.11	5.61	ns

Notes:

1. Software default selection highlighted in gray.
2. For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

B-LVDS/M-LVDS

Bus LVDS (B-LVDS) and Multipoint LVDS (M-LVDS) specifications extend the existing LVDS standard to high-performance multipoint bus applications. Multidrop and multipoint bus configurations may contain any combination of drivers, receivers, and transceivers. Microsemi LVDS drivers provide the higher drive current required by B-LVDS and M-LVDS to accommodate the loading. The drivers require series terminations for better signal quality and to control voltage swing. Termination is also required at both ends of the bus since the driver can be located anywhere on the bus. These configurations can be implemented using the TRIBUF_LVDS and BIBUF_LVDS macros along with appropriate terminations. Multipoint designs using Microsemi LVDS macros can achieve up to 200 MHz with a maximum of 20 loads. A sample application is given in [Figure 2-26](#). The input and output buffer delays are available in the LVDS section in [Table 2-160 on page 2-86](#).

Example: For a bus consisting of 20 equidistant loads, the following terminations provide the required differential voltage, in worst-case Industrial operating conditions, at the farthest receiver: $R_S = 60 \Omega$ and $R_T = 70 \Omega$, given $Z_0 = 50 \Omega$ (2") and $Z_{\text{stub}} = 50 \Omega$ (~1.5").

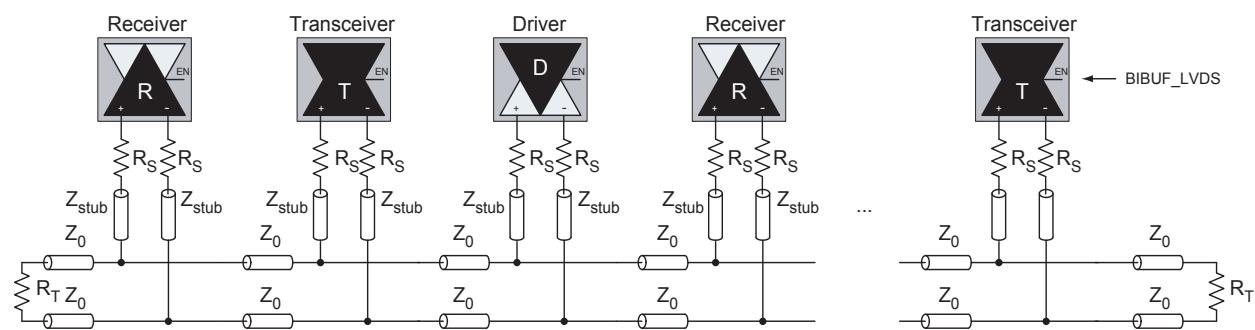


Figure 2-26 • B-LVDS/M-LVDS Multipoint Application Using LVDS I/O Buffers

Input Register

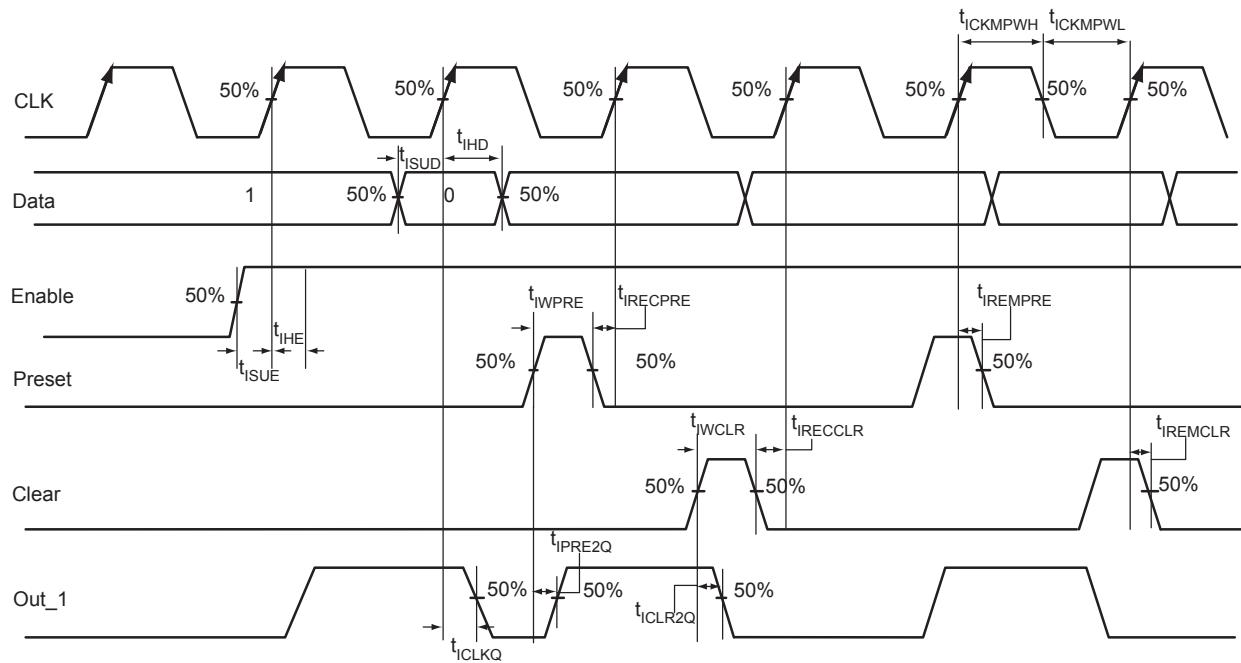


Figure 2-30 • Input Register Timing Diagram

1.5 V DC Core Voltage

Table 2-197 • A3PE600L Global Resource
Military-Case Conditions: $T_J = 125^\circ\text{C}$, $V_{CC} = 1.425 \text{ V}$

Parameter	Description	-1		Std.		Units
		Min.¹	Max.²	Min.¹	Max.²	
t_{RCKL}	Input Low Delay for Global Clock	0.82	1.07	0.97	1.26	ns
t_{RCKH}	Input High Delay for Global Clock	0.81	1.10	0.95	1.30	ns
$t_{RCKMPWH}$	Minimum Pulse Width High for Global Clock					ns
$t_{RCKMPWL}$	Minimum Pulse Width Low for Global Clock					ns
t_{RCKSW}	Maximum Skew for Global Clock		0.30		0.35	ns
F_{RMAX}	Maximum Frequency for Global Clock					MHz

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
3. For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

Table 2-198 • A3PE3000L Global Resource
Military-Case Conditions: $T_J = 125^\circ\text{C}$, $V_{CC} = 1.425 \text{ V}$

Parameter	Description	-1		Std.		Units
		Min.¹	Max.²	Min.¹	Max.²	
t_{RCKL}	Input Low Delay for Global Clock	1.62	1.87	1.90	2.20	ns
t_{RCKH}	Input High Delay for Global Clock	1.61	1.90	1.89	2.24	ns
$t_{RCKMPWH}$	Minimum Pulse Width High for Global Clock					ns
$t_{RCKMPWL}$	Minimum Pulse Width Low for Global Clock					ns
t_{RCKSW}	Maximum Skew for Global Clock		0.30		0.35	ns
F_{RMAX}	Maximum Frequency for Global Clock					MHz

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
3. For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

Table 2-207 • RAM512X18Military-Case Conditions: $T_J = 125^\circ\text{C}$, $V_{CC} = 1.425 \text{ V}$ for A3PE600L and A3PE3000L

Parameter	Description	-1	Std.	Units
t_{AS}	Address setup time	0.26	0.31	ns
t_{AH}	Address hold time	0.00	0.00	ns
t_{ENS}	REN, WEN setup time	0.10	0.11	ns
t_{ENH}	REN, WEN hold time	0.06	0.07	ns
t_{DS}	Input data (WD) setup time	0.19	0.23	ns
t_{DH}	Input data (WD) hold time	0.00	0.00	ns
t_{CKQ1}	Clock High to new data valid on RD (output retained, WMODE = 0)	2.29	2.69	ns
t_{CKQ2}	Clock High to new data valid on RD (pipelined)	0.95	1.12	ns
t_{C2CRWH}	Address collision clk-to-clk delay for reliable read access after write on same address – applicable to opening edge	0.18	0.21	ns
t_{C2CWRH}	Address collision clk-to-clk delay for reliable write access after read on same address – applicable to opening edge	0.21	0.25	ns
t_{RSTBQ}	RESET Low to data out Low on RD (flow through)	0.98	1.15	ns
	RESET Low to data out Low on RD (pipelined)	0.98	1.15	ns
$t_{REMRSTB}$	RESET removal	0.30	0.36	ns
$t_{RECRSTB}$	RESET recovery	1.59	1.87	ns
$t_{MPWRSTB}$	RESET minimum pulse width	0.59	0.67	ns
t_{CYC}	Clock cycle time	5.39	6.20	ns
F_{MAX}	Maximum frequency	185	161	MHz

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

FIFO

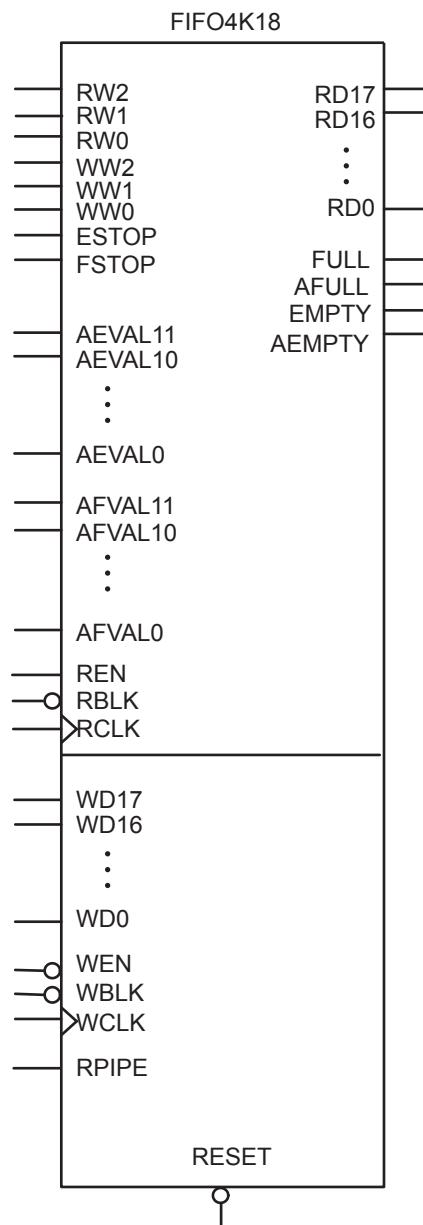


Figure 2-49 • FIFO Model

JTAG 1532 Characteristics

JTAG timing delays do not include JTAG I/Os. To obtain complete JTAG timing, add I/O buffer delays to the corresponding standard selected; refer to the I/O timing characteristics in the "User I/O Characteristics" section on page 2-18 for more details.

Timing Characteristics

Table 2-220 • JTAG 1532

Military-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case VCC = 1.14 V for A3PE600L and A3PE3000L

Parameter	Description	-1	Std.	Units
t_{DISU}	Test Data Input Setup Time	0.80	0.94	ns
t_{DIHD}	Test Data Input Hold Time	1.60	1.88	ns
t_{TMSSU}	Test Mode Select Setup Time	0.80	0.94	ns
t_{TMDHD}	Test Mode Select Hold Time	1.60	1.88	ns
t_{TCK2Q}	Clock to Q (data out)	6.39	7.52	ns
t_{RSTB2Q}	Reset to Q (data out)	26.63	31.33	ns
F_{TCKMAX}	TCK Maximum Frequency	18.70	15.90	MHz
$t_{TRSTREM}$	ResetB Removal Time	0.48	0.56	ns
$t_{TRSTREC}$	ResetB Recovery Time	0.00	0.00	ns
$t_{TRSTMPW}$	ResetB Minimum Pulse	TBD	TBD	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

Table 2-221 • JTAG 1532

Military-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case VCC = 1.425 V for All Dies

Parameter	Description	-1	Std.	Units
t_{DISU}	Test Data Input Setup Time	0.60	0.71	ns
t_{DIHD}	Test Data Input Hold Time	1.21	1.42	ns
t_{TMSSU}	Test Mode Select Setup Time	0.60	0.71	ns
t_{TMDHD}	Test Mode Select Hold Time	1.21	1.42	ns
t_{TCK2Q}	Clock to Q (data out)	6.04	7.10	ns
t_{RSTB2Q}	Reset to Q (data out)	24.15	28.41	ns
F_{TCKMAX}	TCK Maximum Frequency	22.00	19.00	MHz
$t_{TRSTREM}$	ResetB Removal Time	0.00	0.00	ns
$t_{TRSTREC}$	ResetB Recovery Time	0.24	0.28	ns
$t_{TRSTMPW}$	ResetB Minimum Pulse	TBD	TBD	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

3 – Pin Descriptions and Packaging

Supply Pins

GND**Ground**

Ground supply voltage to the core, I/O outputs, and I/O logic.

GNDQ**Ground (quiet)**

Quiet ground supply voltage to input buffers of I/O banks. Within the package, the GNDQ plane is decoupled from the simultaneous switching noise originated from the output buffer ground domain. This minimizes the noise transfer within the package and improves input signal integrity. GNDQ must always be connected to GND on the board.

VCC**Core Supply Voltage**

Supply voltage to the FPGA core, nominally 1.5 V for A3P250 and A3P100 devices and 1.2 V or 1.5 V for A3PE600L and A3PE3000L devices. VCC is required for powering the JTAG state machine in addition to VJTAG. Even when a device is in bypass mode in a JTAG chain of interconnected devices, both VCC and VJTAG must remain powered to allow JTAG signals to pass through the device.

For A3PE600L and A3PE3000L devices, VCC can be switched dynamically from 1.2 V to 1.5 V or vice versa. This allows in-system programming (ISP) when VCC is at 1.5 V and the benefit of low power operation when VCC is at 1.2 V.

VCCI_{Bx}**I/O Supply Voltage**

Supply voltage to the bank's I/O output buffers and I/O logic. Bx is the I/O bank number. There are up to eight I/O banks on low power flash devices plus a dedicated VJTAG bank. Each bank can have a separate VCCI connection. All I/Os in a bank will run off the same VCCI_{Bx} supply. VCCI can be 1.5 V, 1.8 V, 2.5 V, or 3.3 V, nominal voltage. Unused I/O banks should have their corresponding VCCI pins tied to GND.

VMV_x**I/O Supply Voltage (quiet)**

Quiet supply voltage to the input buffers of each I/O bank. x is the bank number. Within each I/O bank, the VMV and VCCI are connected to each other to improve the ESD discharge path for any I/O pin against its VMV pin. Each bank must have at least one VMV connection, and no VMV should be left unconnected. All I/Os in a bank run off the same VMV_x supply. VMV is used to provide a quiet supply voltage to the input buffers of each I/O bank. VMV_x can be 1.2 V (A3PE600L and A3PE3000L only), 1.5 V, 1.8 V, 2.5 V, or 3.3 V, nominal voltage. Unused I/O banks should have their corresponding VMV pins tied to GND. VMV and VCCI should be at the same voltage within a given I/O bank. Used VMV pins must be connected to the corresponding VCCI pins of the same bank (i.e., VMV0 to VCCI_{B0}, VMV1 to VCCI_{B1}, etc.).

VCCPLA/B/C/D/E/F**PLL Supply Voltage**

Supply voltage to analog PLL, nominally 1.5 V or 1.2 V, depending on the device.

- 1.5 V for A3P250 and A3P1000 devices
- 1.2 V or 1.5 V for A3PE600L or A3PE3000L devices

When the PLLs are not used, the Microsemi Designer place-and-route tool automatically disables the unused PLLs to lower power consumption. The user should tie unused VCCPLx and VCOMPLx pins to ground. Microsemi recommends tying VCCPLx to VCC and using proper filtering circuits to decouple VCC noise from the PLLs. Refer to the PLL Power Supply Decoupling section of the "Clock Conditioning Circuits in Low Power Flash Devices and Mixed Signal FPGAs" chapter of the [Military ProASIC3/EL Device Family User's Guide](#) for a complete board solution for the PLL analog power supply and ground.

- There is one VCCPLF pin on A3P250 and A3P1000 devices.
- There are six VCCPLX pins on A3PE600L and A3PE3000L devices.

FG484	
Pin Number	A3P1000 Function
Y3	NC
Y4	IO182RSB2
Y5	GND
Y6	IO177RSB2
Y7	IO174RSB2
Y8	VCC
Y9	VCC
Y10	IO154RSB2
Y11	IO148RSB2
Y12	IO140RSB2
Y13	NC
Y14	VCC
Y15	VCC
Y16	NC
Y17	NC
Y18	GND
Y19	NC
Y20	NC
Y21	NC
Y22	VCCIB1
AA1	GND
AA2	VCCIB3
AA3	NC
AA4	IO181RSB2
AA5	IO178RSB2
AA6	IO175RSB2
AA7	IO169RSB2
AA8	IO166RSB2
AA9	IO160RSB2
AA10	IO152RSB2
AA11	IO146RSB2
AA12	IO139RSB2
AA13	IO133RSB2
AA14	NC
AA15	NC

FG484	
Pin Number	A3P1000 Function
AA16	IO122RSB2
AA17	IO119RSB2
AA18	IO117RSB2
AA19	NC
AA20	NC
AA21	VCCIB1
AA22	GND
AB1	GND
AB2	GND
AB3	VCCIB2
AB4	IO180RSB2
AB5	IO176RSB2
AB6	IO173RSB2
AB7	IO167RSB2
AB8	IO162RSB2
AB9	IO156RSB2
AB10	IO150RSB2
AB11	IO145RSB2
AB12	IO144RSB2
AB13	IO132RSB2
AB14	IO127RSB2
AB15	IO126RSB2
AB16	IO123RSB2
AB17	IO121RSB2
AB18	IO118RSB2
AB19	NC
AB20	VCCIB2
AB21	GND
AB22	GND

FG896	
Pin Number	A3PE3000L Function
H26	IO84NDB2V0
H27	IO96PDB2V1
H28	IO96NDB2V1
H29	IO89PDB2V0
H30	IO89NDB2V0
J1	IO290NDB7V2
J2	IO290PDB7V2
J3	IO302NDB7V3
J4	IO302PDB7V3
J5	IO295NDB7V2
J6	IO299NDB7V3
J7	VCCIB7
J8	VCCPLA
J9	VCC
J10	IO04NPB0V0
J11	IO18NDB0V2
J12	IO20NDB0V2
J13	IO20PDB0V2
J14	IO32NDB0V3
J15	IO32PDB0V3
J16	IO42PDB1V0
J17	IO44NDB1V0
J18	IO44PDB1V0
J19	IO54NDB1V1
J20	IO54PDB1V1
J21	IO76NPB1V4
J22	VCC
J23	VCCPLB
J24	VCCIB2
J25	IO90PDB2V1
J26	IO90NDB2V1
J27	GBB2/IO83PDB2V0
J28	IO83NDB2V0
J29	IO91PDB2V1
J30	IO91NDB2V1
K1	IO288NDB7V1